



**UNITED STATES DEPARTMENT OF COMMERCE  
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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.
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EXAMINER
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ART UNIT	PAPER NUMBER
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DATE MAILED:

**Please find below and/or attached an Office communication concerning this application or proceeding.**

**Commissioner of Patents and Trademarks**



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DEA/FCE-1994

SERIAL NUMBER	FILING DATE	FIRST NAMED APPLICANT	ATTORNEY DOCKET NO
08/832,443			

EXAMINER	
ART UNIT	PAPER NUMBER
	11

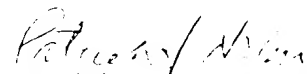
DATE MAILED

Please find below a communication from the EXAMINER in charge of this application

Commissioner of Patents

1. The communication filed on 7-16-98 is not fully responsive to the communication mailed 2-27-98 for the reason(s) set forth on the attached Notice to Comply with the Sequence Rules or CRF Diskette Problem Report.
2. Since the above-mentioned reply appears to be *bona fide*, applicant is given a TIME PERIOD of **ONE (1) MONTH** or **THIRTY (30) DAYS**, from the mailing date of this notice, whichever is longer, within which to supply the omission or correction in order to avoid abandonment. EXTENSIONS OF THIS TIME LIMIT MAY BE GRANTED UNDER 37 CFR 1.136(a).
3. In addition, Applicant is requested to submit a substitute claim 47, which has support in the specification as originally filed, since the originally filed claim is unreadable.
4. Any inquiry concerning this communication should be directed to Examiner Patrick Nolan, Art Unit 1644, whose telephone number is (703)- 305-1987.
5. Any questions regarding compliance with the sequence rules requirements specifically should be directed to the departments listed at the bottom of the Notice to Comply.

Patrick J. Nolan, Ph.D.  
May 25, 1999

  
Patrick J. Nolan, Ph.D.  
Patent Examiner